



MICROCOPY RESOLUTION TEST CHART NATIONAL BUREAU OF STANDARDS-1963-A

REPORT DOCUMENTATION PAGE						
18. REPORT SECURITY CLASSIFICATION UNCLASSIFIED		1b. RESTRICTIVE MARKINGS				
26 SECURITY CLASSIFICATION AUTHORITY		3. DISTRIBUTION/AVAILABILITY OF REPORT Approved for public release:				
26. DECLASSIFICATION/DOWNGRADING SCHEDULE		distribution unlimited.				
4. PERFORMING ORGANIZATION REPORT NUMBER(S)		5. MONITORING ORGANIZATION REPORT NUMBER(S) AFOSR-TR- 87-1742				
6a NAME OF PERFORMING ORGANIZATION Colorado State University	8b. OFFICE SYMBOL (If applicable)	7a. NAME OF MONITAFOSR/NE	TORING ORGAN	IZATION		
6c. ADDRESS (City. State and ZIP Code) Colorado State University Department of Electrical Engineering Fort Collins, Colorado 80523		7b. ADDRESS (City. State and ZIP Code) Bldg 410 Bolling AFB, Washington DC 20332-6448				
Bo. NAME OF FUNDING/SPONSORING ORGANIZATION	8b. OFFICE SYMBOL (If applicable)	9. PROCUREMENT INSTRUMENT IDENTIFICATION NUMBER				
Same as 7a	NE	AFOSR-87-002	8	17267		
Sc. ADDRESS (City, State and ZIP Code)		10. SOURCE OF FU	NDING NOS.	088		
Same as 7b		PROGRAM ELEMENT NO.	PROJECT NO.	ANO OUNIT		
11. TITLE (Include Security Classification) Gas Source MBE		61102F	2917	A3 3		
12. PERSONAL AUTHORIS) Professor Gary Robinson			<u> </u>			
13a TYPE OF REPORT 13b. TIME COVERED 14. DATE OF REPORT (Yr., Mo., Day) 15. PAGE SOUNT Final FROM 10-1-86 TO 09-10-87 Nov 87 10						
16. SUPPLEMENTARY NOTATION						
17. COSATI CODES	18. SUBJECT THINS IC	ontinue on reverse if ne	cessary and identi	ify by block number)		
FIELD GROUP SUB. GR.	nolecular	· beam	epita			
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This report describes the equipment acquired and the research performed under the DoD University Research Instrumentation Program grant for "Gas Source MBE" at Colorado State University. The objective of the research supported by the grant is to grow epitaxial III-V semiconductor films using gaseous source materials for molecular beam epitaxy (MBE). The grant provided the critical equipment items needed to customize the existing commercial MBE system and allow growth of heteroepitaxial structures that can not be fabricated by other techniques. The resulting gas source MBE materials could provide the optoelectronic device technology required for the high data rate signal processing of the vast quantities of input data expected in future DoD space and ground-based sensing systems.						
20. DISTRIBUTION/AVAILABILITY OF ABSTRACT		21. ABSTRACT SECU	JAITY CLASSIFI	CATION		
UNCLASSIFIED/UNLIMITED W SAME AS RPT.						
22. NAME OF RESPONSIBLE INDIVIDUAL		22b. TELEPHONE NI (Include Area Co		22c. OFFICE SYMBOL		
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AFOSR-TR. 87-1742

Final Report

to the

Air Force Office of Scientific Research

for

University Research Instrumentation Program
Grant No. AFOSR-87-0028
(1 Oct. 1986 to 30 Sept. 1987)
\$194,000

entitled

"Gas Source MBE"

at

Colorado State University

Fort Collins, CO 80523

PI: Gary Y. Robinson

Department of Electrical Engineering

(303) 491-6575

November 1987



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Final Report

AFOSR Grant #AFOSR-870-0028

I. Summary

This report describes the equipment acquired and the research performed under the DoD University Research Instrumentation Program grant for "Gas Source MBE" at Colorado State University. The grant began on October 1, 1986, was of 12-months duration, and provided \$194,000 in funding.

The objective of the research supported by the grant is to grow epitaxial III-V semiconductor films using gaseous source materials for molecular beam epitaxy (MBE). The grant provided the critical equipment items needed to customize an existing commercial MBE system and allow growth of heteroepitaxial structures that can not be fabricated by other techniques. The resulting gas source MBE materials could provide the optoelectronic device technology required for the high data rate signal processing of the vast quantities of input data expected in future DoD space- and ground-based sensing systems.

II. List of Equipment

The following items of equipment have been purchased with funds provided by this URIP grant. All items have been received and are currently in use; the items are numbered as in the original proposal.

Item #1

Gas storage cabinets with automatic shut off;
gas delivery system with leak valves and provision
for computer control; custom designed for CSU
Precision Flow Devices; MKS Instruments;
Bush Electronics.

\$39,544

Leak-free fittings and gas lines for connecting gas delivery system to existing MBE equipment	
MDC Components; Omega; Denver Valve and Fitting	3,546
High temperature heater and molybdenum blocks for sample mounting and cleaning during testing of gas flow system Perkin-Elmer Corporation	5,147
Optical pyrometer for temperature measurement	·
during gas flow experiments Williamson 3100	1,459
Glove/dry box for sample introduction without escape of hazardous gas; custom designed for CSU	
Southwest Plastics TOTAL	924 \$50,620
<pre>Item #2 Primary toxic gas sensor with high sensitivity and automatic logging of gas levels in laboratory</pre>	\$ 8,005
Secondary toxic gas sensor with low maintenance for monitoring exhaust effluent International Sensor Technology Model AG3100	1,299
Self contained breathing apparatus for use in toxic atmospheres Scott Air Pack 2.2	1,658
Uninterruptible power source for above toxic gas sensors	
BFA Corporation	1,070
Portable hazardous gas leak detector to be used during changing of gas tanks Matheson 8057	988
HEPA vacuum cleaner for removal of hazardous materials Lab Safety D1950 TOTAL	677 \$13,697
	4,
Item #3 Cryopump with closed-cycle He refrigerator and special vent valve and UHV gate valve for pumping H ₂ gas load	
CTI-Cryogenics CT-8 and VAT10146	14,205

Mechanical vacuum pump with non-reactive pump fluid and demountable filter system Alcatel 2012/93169	5,262
Heat exchanger for cooling MBE system during H ₂ pumping Neslab HX-150	4,951
Vacuum components and hardware for interconnecting cryopump and mechanical pump MDC Vacuum Components and Granville-Phillips	3,278
Storage tank for liquid N ₂ for cooling sublimation pumps to reduce H ₂ gas load Minnesota Valley Engineering TOTAL	1.800 \$29,496
Item #4 Residual gas analyzer with quadrupole mass spectrometer Baltzers 120/420 (additional funding from other sources for total of \$30,175)	10,055
Vacuum pump, capacitance manometer, flow controller for residual gas analysis Baltzers PMS01702;MKS Instruments 222/1259	9,465
Data acquisition system for residual gas analysis with switch control unit and plotter compatible with existing computer Hewlett-Packard 3488/7440	3,011
Camera for data recording Tektronic C-53P TOTAL	1.325 \$23,856
Item #5 New X-ray diffractometer with computer-controlled double crystal X-ray spectrometer, X-ray generator, scintillation counter and electronics, and refurbished 9-29 diffractometer Northeast Analytical Corp; Bede Model 6; Hiltonbrooks; General Electric (additional funding from other sources for total of \$65,600)	52,200
Computer system for X-ray diffractometer IBM AT: Epson 100; Hewlett Packard 7440 TOTAL	6.746 \$58,946

\$17,785

All of the above six items were requested in the original proposal and the available funds met the intended need. The final costs for Items 1 and 3 were higher than the estimates in the proposal; however it was not necessary to request additional funds since the costs of Items 2.4.5, and 6 charged to this grant were substantially less than originally estimated. The purchase of Items 4 and 5 were cost shared with funds from other sources, and Items 2 and 6 were purchased at lower cost than anticipated.

III. DoD Research Projects Utilizing URIP Equipment

 "Base Technology Support for InP/InGaAs Device and Circuit Development"

P.I.: D. L. Lile

Co-PIs: G. Y. Robinson and C. W. Wilmsen

Agency: Department of Air Force
Rome Air Development Center

Hanscom AFB, MA 01721

Contract =: SUB8218 Amount: \$100,000 Duration: 7/85 - 6/86

This was a one-year contract to establish a new research program at Colorado State University in the device technology of InP and InGaAs insulated gate FETs for application in future mm-wave circuits. The III-V semiconductors InP and InGaAs exhibit high values of electron mobility and saturation velocity and thus are ideal candidates for high frequency and high speed FETs. The program included the CVD growth of dielectric layers for gate insulators using a custom-designed low temperature plasma-enhanced

reactor with in-situ monitoring of the dielectric-semiconductor interface, the analysis of the dielectric-InP interface by deep level transient spectroscopy (DLTS) using a computer controlled data acquisition and analysis system, and chemical assessment of the dielectric-semiconductor interface using XPS and SIMS as well as structural assessment using high resolution cross-sectional TEM. The MBE and DLTS portions of the program were under the direction of G. Y. Robinson while D. L. Lile was responsible for dielectric growth and C. W. Wilmsen supervised the chemical and structural characterizations.

The intent of the Air Force support was to help establish at CSU a viable III-V materials and devices activity for future research in monolithic mm-wave integrated circuits as well as optoelectronic devices. This required an inhouse epitaxial growth capability in order to achieve the performance predicted for optimumly designed InP and InGaAs MISFETs. The equipment Items 1.2.3, and 4 listed in this proposal were necessary for the InGaAs films already grown and the InP films to be grown and used for our MIS studies. Furthermore, the same equipment will be used for growth of heteroepitaxial structures of InP/InGaAs/InP. The double-crystal X-ray diffractometer in Item 5 is being used to determine the lattice mismatch of the InGaAs/InP interface and has greatly aided in establishing the growth conditions for device quality InGaAs. Beam fluxes and alloy composition x have been determined with Item 5 and film thickness with Item 6.

2. "Beam Assisted Fabrication of III-V/Si Monolithic Devices"

PI: G. Y. Robinson

Co-PIs: G. J. Collins and R. Solanki Agency: Department of the Air Force

Air Force Office of Scientific Research

Contract #: F49620-86-K-0021

Amount: \$343,989

Duration: 11 September 1986 to 10 September 1988

The objective of this research project is to explore two new methods for deposition of III-V semiconducting films on Si substrates. Using gassource molecular beam epitaxy (MBE) and photon-beam and electron-beam assisted metal-organic chemical vapor deposition (MOCVD), GaAs and other III-V films with abrupt heterojunctions are being formed epitaxially on Si, and by means of optical and electrical characterization the suitability of the resulting III-V/Si structures are being examined for use in monolithic devices.

and PH₃ to produce beams of As₂ and P₂, respectively, with conventional MBE technology for Group-III molecular beam production from effusion cells. The availability of both As₂ and P₂ beams allows incorporation of buffer layers of wide composition range and lattice parameters and for exploration of III-V materials grown by MBE on Si other than GaAs. Item 1 is the gas delivery system which provides the precise control and rapid switching of the PH₃ and AsH₃ flow rates needed to grow superlattices and other heterostructures containing both As and P. Item 3 is the pumping system needed for accommodating the large H₂ load and for safe removal of the toxic hydrides. Item 2 is the safety equipment required for the hazardous materials involved. Item 4 has been used for analysis of the vacuum system and gas control system of Itam 1. Items 5 and 6 have been extensively employed in characterizing the GaAs on Si and GaAs/InGaAs superlattices grown under this program.

3. "Growth of Semiconductor Heterostructures by Gas-Source MBE"

PI: G. Y. Robinson

Agency: Naval Research Laboratory Washington, DC 20375

Contract #: N00014-87-K-2044

Amount: \$123,000

Duration: 30 July 1987-1 August 1989

Although MBE has become a mature epitaxial growth technology for fabrication of GaAs/AlGaAs structures, its application to other semiconductor materials has been hindered by the high vapor pressure of some elements when evaporated from the solid phase. These high pressures lead to practical difficulties when introducing these elements into an ultra-high vacuum system in a well controlled manner. The use of gaseous sources in MBE is in its early stages of development and appears to offer a practical means of handling relatively volatile elements. The resulting gas-source MBE technology combines the capability of producing thin film structures with interface abruptness on the atomic scale by using the line-of-sight molecular beams of MBE with the precise control of composition using the mass flow controllers of chemical vapor deposition. Thus gas-source MBE permits the growth of QW heterostructures with materials that have been previously impossible or very difficult to grow by conventional MBE or other epitaxial growth methods. The objectives of this research program are the following:

- * To implement gas-source MBE technology and demonstrate the growth of high quality QW heterostructures using the InGaAs/InP system. Other materials systems will also be considered after qualification with InGaAs/InP.
- * To transfer gas-source MBE technology to industry for increasing the output of commercial MBE production equipment.
- * To explore in collaboration with researchers at NRL and other designated DoD laboratories, the application of gas-source MBE for the growth of non-conventional materials suitable for long wavelength detectors and sources.

All of the equipment purchased under the URIP grant is being used in this research project.

4. "Semiconducting Transition Metal Silicides: New Materials for Optoelectronics on Silicon"

PI: J. E. Mahan

Co-PI: G. Y. Robinson

Agency: National Science Foundation and

Army Research Office

Contract #: ECS-85-1-4842 Amount: \$69,995 (1st year) Duration: 5/1/87 - 4/30/89

The principal thrust of this research is to experimentally characterize the optical, electronic transport, and photoelectronic properties of the narrow bandgap semiconducting silicides. The potential applications of the semiconducting silicides include (1) electro-optic interconnects for silicon microelectronics, (2) monolithic fiber optic sources, detectors, and signal processing electronics, and (3) improved silicon-based infrared detectors. The prospects for achieving epitaxial growth of several of these materials are good, and the primary objective of this work is to demonstrate how large area single crystal films can be formed. Items 5 and 6 are being used extensively to characterize the films grown under this and related contracts.

IV. Other Research of Interest to DoD

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1. "Center for Optoelectronic Computing Systems"

PI: W. T. Cathey, University of Colorado - Boulder

Co-PIs: G. Y. Robinson and 4 faculty at Colorado State University;

16 faculty at University of Colorado-Boulder.

Agencies: National Science Foundation Engineering Research Center;

Colorado Advanced Technology Institute; Industry.

Amount: NSF \$14 million (5 years)

State \$3.0 million (5 years)

Industry \$0.5 million (first year).

The objective of this research program is to substantially advance the field of optical computing by developing three new proof-of-principle computing machines that take advantage of the speed, parallelism, and

connectivity of optical information transfer. The task of the investigators at Colorado State University is to provide III-V optoelectronic devices uniquely designed for the proof-of-principle machines. The initial research focuses on realization of a high speed two-dimensional electricallyaddressable spatial light modulator (SLM) which will employ a metalinsulator-semiconductor charge coupled device (CCD). To maximize the modulation efficiency, the CCD array will be built on a multiple quantum well (MQW) heteroepitiaxial structure grown by gas-source MBE. We are currently growing MQWs of InGaAs/GaAs and will be growing MQWs of InGaAs/InP using the gas-source MBE equipment purchased under the URIP grant. The capability to abruptly change from an arsenide (InGaAs) to a phosphide (InP) in a distance of a few lattice constants or less, which is only possible with gas-source MBE, provides the means of engineering the III-V heterostructures for optimum optoelectronic properties. Device other than the CCD SLM that are currently under development are an optically addressed optical switch and a surface emitting laser array.

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